AN720

Measuring Temperature Using the Watchdog Timer (WDT)

Author: Ian Lao
Microchip Technology Inc.
Chandler, AZ

INTRODUCTION

This application note shows how Microchip Technology's Watchdog Timer (WDT) can be used to acquire rough temperature measurements.

Recent advances in sensor technology have allowed for the development of many different sensors to measure temperature. However, almost all of these are implemented as dedicated function sensors.

Microchip has now developed a method of combining both rough temperature sensing and microcontroller functionality on the same device, without the need for external components.

Preliminary analysis of the on-board WDT shows a piece wise linear correlation between temperature and the time-out period of the WDT. The WDT time-out period appears to increase for a fixed V_{DD} as temperature increases. Tests indicate that this property may be used for cost effective rough temperature sensing.

The WDT module is similar across many families of microcontrollers from Microchip. This allows for a wide range of different applications to be developed using the same technique.

Though actual application results may differ, an accuracy of up to $\pm$1°C may be seen. The linearity of the WDT is not guaranteed, but has been observed.

Note:	It is up to the user to test the device in the system to determine accuracy/usability.

THEORY

The WDT is an 8-bit timer with an 8-bit prescaler option, driven from a free running on-chip RC oscillator. This oscillator is completely independent of pins OSC1/CLKIN, OSC2/CLKOUT, and the INTRC oscillator. As with any RC oscillator, variances in temperature will affect the frequency of the circuit. Cumulative effects will therefore, show up as a change in the time-out period of the WDT.

By utilizing another timer as a reference, a sample may be established, whereby changes in the WDT time-out period can be measured. Calibrated temperature can then be derived via Equation 1.

EQUATION 1:

CC = COUNT*Scalar - Offset

CC => calibrated count value

C => COUNT; number of times TMR0 has rolled over

Offset => calibration offset due to voltage variance or self-heating (determined by testing against a known fixed temperature)

Scalar => calibration scalar due to process or application design ("slope" determined by testing 2 known temperatures)

Process variations across lots, part families, and different cores are expected. Since the WDT is clocked by an RC oscillator, these differences are expected to influence the "slope" of the piece wise linear WDT response (see Figure 5A and Figure 5B).

HARDWARE REQUIRED

1. Voltage/temperature regulated power supply
2. Temperature-compensated oscillator or crystal clock source

Note:	If the INTRC is used for the reference timer, no external clock components are required to implement this design. For greater accuracy, an external temperature-compensated oscillator may be used.

IMPLEMENTATION

Resources Used

This design uses two timers and a 16-bit count register to count the number of times TMR0 has rolled over since the last WDT time-out. Two calibration constants are used to negate the effects of self-heating and process variation/application design.

1. Reference Timer (TMR0);
   The reference timer may be implemented using the INTRC or an external temperature-compensated clock source to drive TMR0.
2. Measurement Timer (WDT);
   The WDT is utilized as the measurement timer. It is configured to use the on-board pre-scaler that is set to a ratio of 1:8 in this example. A ratio of 1:8 was chosen to allow the 16-bit count register to capture usable TMR0 rollovers without overflowing. This ratio also allows for a granularity in the count register, small enough to detect changes in temperature.

Note: Users should test their code to determine the appropriate prescaler ratio to use in their application.

Firmware

Once TMR0 and WDT are configured, both are released to begin incrementing. A 16-bit register is used to count the number of times TMR0 rolls over (COUNT). TMR0 is allowed to continue incrementing and rolling over until the WDT times out. This COUNT is then used as the input to Equation 1 to give a resultant calibrated count.

Use caution when interrupts other than TMR0 (for devices that have interrupts) are active during rough temperature measurements, to ensure capturing all TMR0 rollover events. WDT time-outs are asynchronous events. Missing a TMR0 rollover will add to the error of the reading.

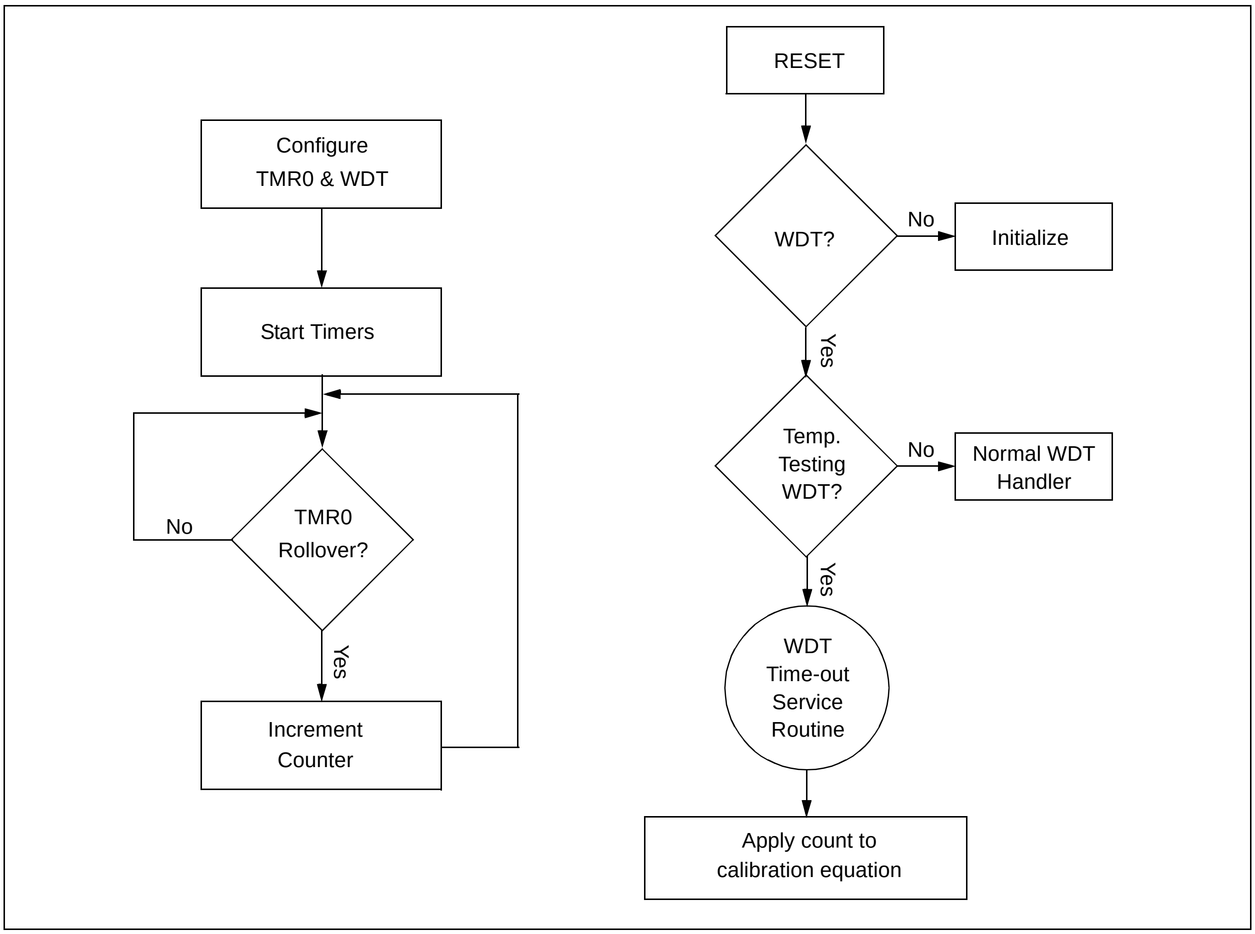
A look-up table or algorithm may be used to convert the calibrated count to Fahrenheit or Celsius for display.

Figure 1 illustrates the flow diagram for this program.

Appendix A is the source code listing.

Note: The part must not be put into SLEEP mode during temperature measurements, as SLEEP mode disables TMR0.

FIGURE 1: FIRMWARE FLOW DIAGRAM



CALIBRATION

In using the WDT to measure temperature, calibration of the microcontroller against system errors is required. Since the WDT is piece wise linear with temperature, we know that the two major components of error are the Scalar (Slope) of the line and the "offset" of the line. Process variations in the RC oscillator, which clocks the WDT and the application design itself, will influence the value of the Scalar. Variations in operating voltage and self-heating will produce similar variations in “offset” (see Figure 2 through Figure 5B).

In order to calibrate a part to measure temperature, both of these coefficients must be determined and stored in memory for future use. Two dedicated memory locations (normally near the end of memory) are used to store them. Users should write their application program to include a calibration mode that uses the WDT temperature measurement mechanism, but outputs the uncalibrated count values onto the port pins. This program is then run against two known calibration temperatures. The difference in count values divided by the difference in known temperatures is the Scalar. By assigning a calibrated COUNT value to one of the two known calibration temperatures and solving Equation 1, the "offset" can be determined. In-Circuit Serial Programming™ (ICSP) mode or Serial EEPROM can then be used to store the two calibration values.

All of the sources of error mentioned under that heading should also be taken into consideration when calibrating.

EXAMPLE 1:

Calibration example assuming:

1. Fixed temperature-compensated V_{DD}
2. Fixed temperature-compensated reference oscillator
3. Area of temperature interest: +25°C - +75°C
4. Measured uncalibrated COUNTS @ +25°C Calibration Point 1: COUNT = 475 decimal
5. Measured uncalibrated COUNTS @ +75°C Calibration Point 2: COUNT = 595 decimal

To calculate the Scalar (Slope), the formula is:

$$\text{Scalar} = \frac{\text{Cal Point 2 - Cal Point 1}}{\text{Temp Cal Point 2 - Temp Cal Point 1}}$$

$$\text{Scalar} = \frac{595 - 475}{+75°C - +25°C} = 2.4\ \text{COUNT/°C}$$

Scalar = 2.4 COUNT/°C

To calculate the offset, the formula is:

Assigned Cal. COUNT Value = COUNT x Scalar - Offset

Assume Assigned Value = 0

0 = COUNT x Scalar - Offset

Offset = COUNT x Scalar

@ +25°C Offset = Uncal. COUNT x Scalar

1140.0 = 475 x 2.4

Now Scalar = 2.4 and Offset = 1140.0

EXAMPLE 2:

To make a calibrated COUNT calculation @ 55°C:

CC = COUNT x Scalar - Offset

@ +55°C 192 = 555.0 x 2.4 - 1140.0

SOURCES OF ERROR

When taking temperature measurements, errors may be introduced into the calculations. The most common sources of errors are:

1. Insufficient soak time;
   A certain amount of time is required for any system to stabilize. The varying materials used typically require time to reach thermal equilibrium.
2. Insufficient acquisition time;
   Total acquisition time is typically represented by the equation:

   $T_{Aq} = T_{Soak} + T_{Sample}$

   T_{Aq} => acquisition time. Total time to make a calibrated measurement.

   T_{Soak} => soak time to reach thermal equilibrium

   T_{Sample} => time required to capture a number of uncalibrated COUNTS and average the result of the raw data through a "debounce" algorithm
3. Calibration errors;
   Errors may be introduced by incorrectly determining the Scalar or Offset values. Both of these equation terms are based on controlled known temperatures.
4. Sample error;
   Since temperature does not change quickly (i.e., in the milliseconds), typical applications will apply an algorithm similar to "debounce" that will filter out momentary spikes and steps in temperature readings.
5. Power supply;
   Variances in power supply voltage will effect the INTRC, external oscillator and WDT RC oscillator.
6. Reference oscillator;
   Variances in the reference oscillator due to process, voltage or temperature will affect TMR0.

COMMON USES

Many designs typically use rough temperature data as trip points to indicate over-heating or operation below recommended minimum temperature specifications. Other uses may include but are not limited to:

1. Rough calibration of other hardware/systems/processes
2. Temperature hysteresis measurements

EXPERIMENTAL DATA

The data in Figure 2 was collected using a sample of 8 typical production PIC12C509A parts from the same manufacturing lot. A test board containing all eight parts was then given a soak time of thirty minutes at each tested temperature. Five hundred uncalibrated raw data COUNTS were then recorded and averaged for each tested temperature to produce Figure 2.

- Voltage was supplied and measured via a Topward 3303D DC power supply and Fluke model 87 DMM, respectively.
- A Hart Scientific High Precision Bath Model 7025 with Hart Scientific Black Stack Temperature Probe model 2560 provided the various different temperatures.
- Data was captured using Hyperterminal running on a Windows 95 configured PC.

FIGURE 2: UNCALIBRATED COUNT DATA (V_{DD} = 5.0V)

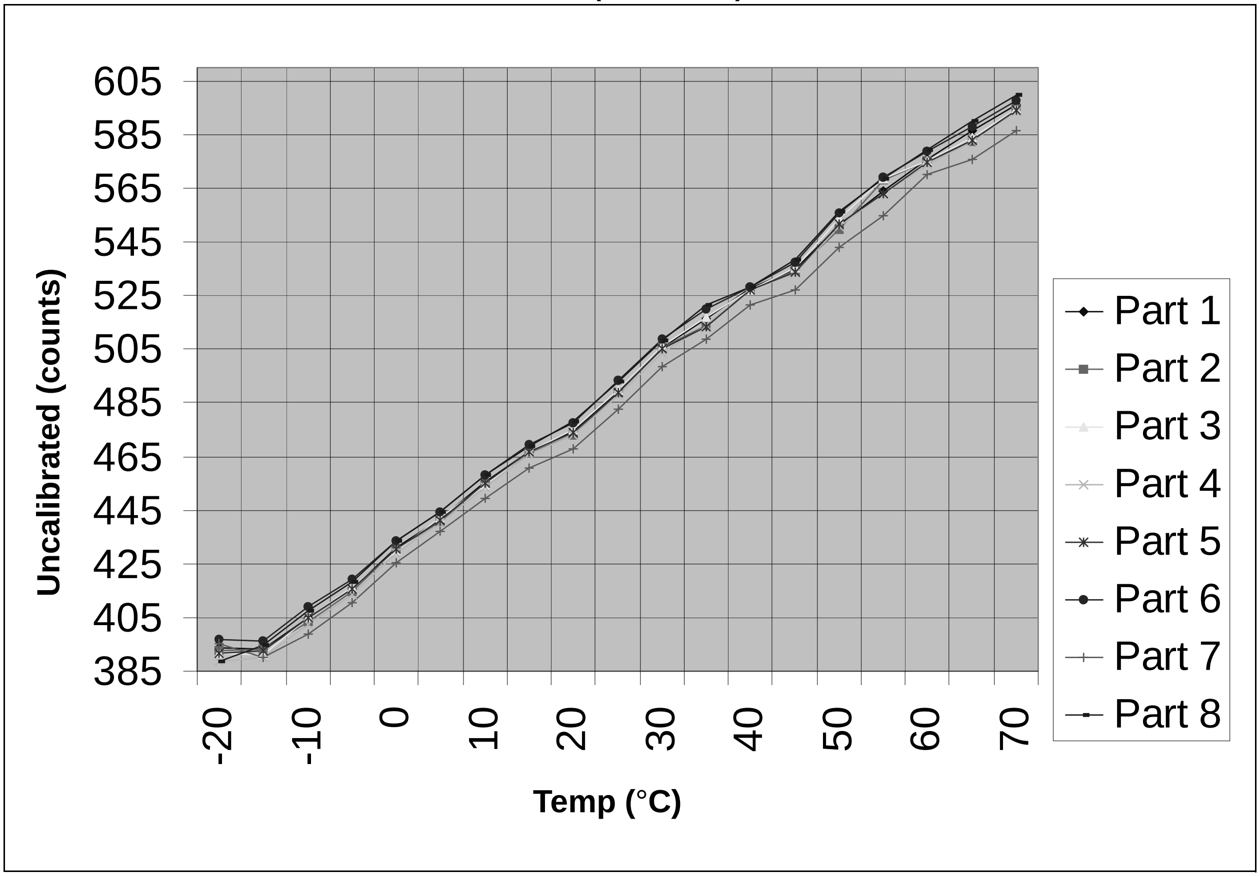


Figure 3A illustrates the effect of variation in power supply voltage on both the offset and slope of the uncalibrated count data in Figure 2. Note for this example, the data from all eight samples was averaged to reduce complexity in the graph.

FIGURE 3A: RAW COUNT VARIANCE DUE TO POWER SUPPLY

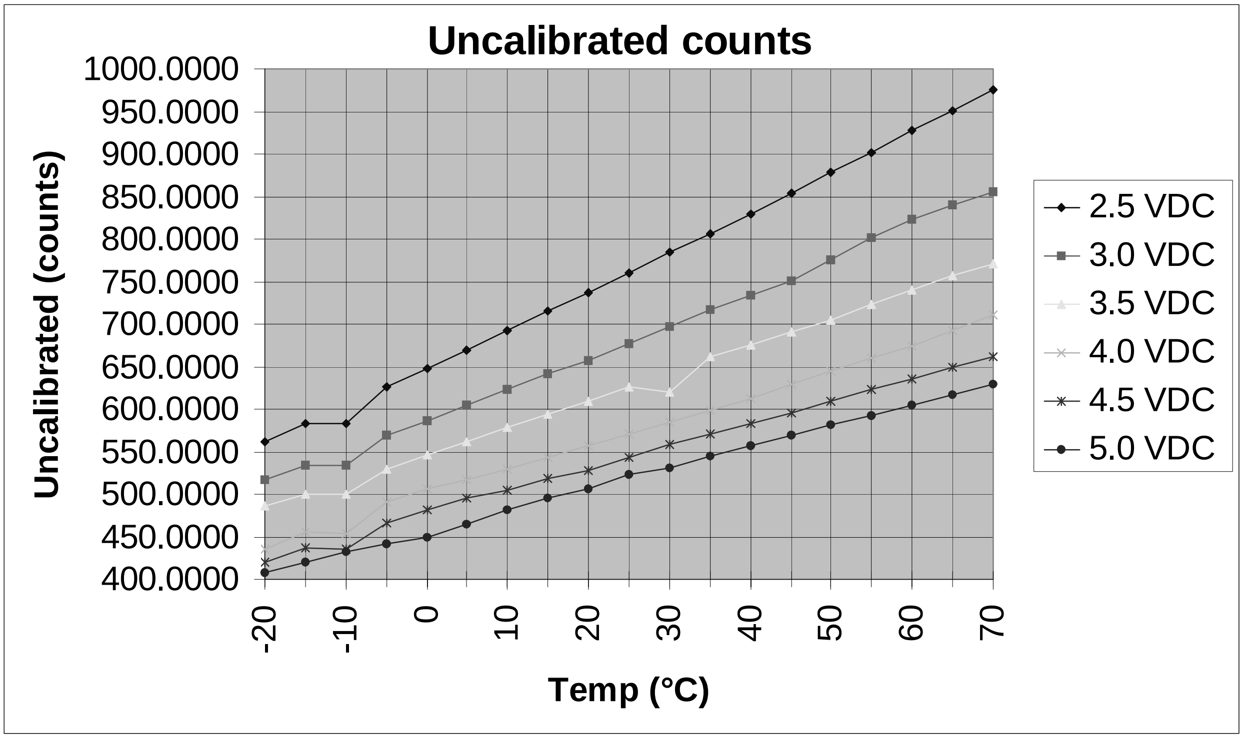


Figure 3B shows a subset of the power supply variance data from Figure 3A. In Figure 3B, the temperature is fixed at 25°C and the data has been expanded to show the data from each unit individually.

FIGURE 3B: VARIANCE DUE TO POWER SUPPLY, BY UNIT

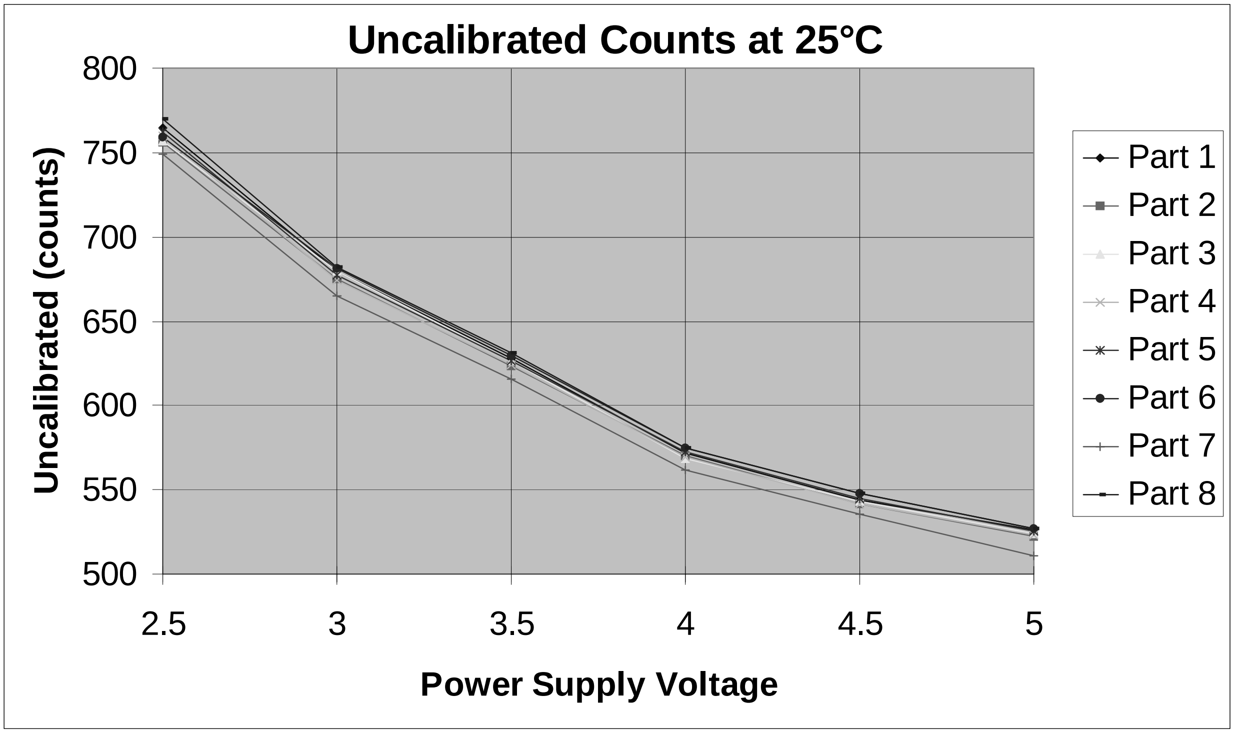


Figure 4 illustrates the standard deviation of the five hundred uncalibrated count data points collected to generate the uncalibrated count averages listed in Figure 2. The three parts with the greatest deviation are listed.

FIGURE 4: ACROSS RAW DATA POINTS (V_{DD} = 5.0V)

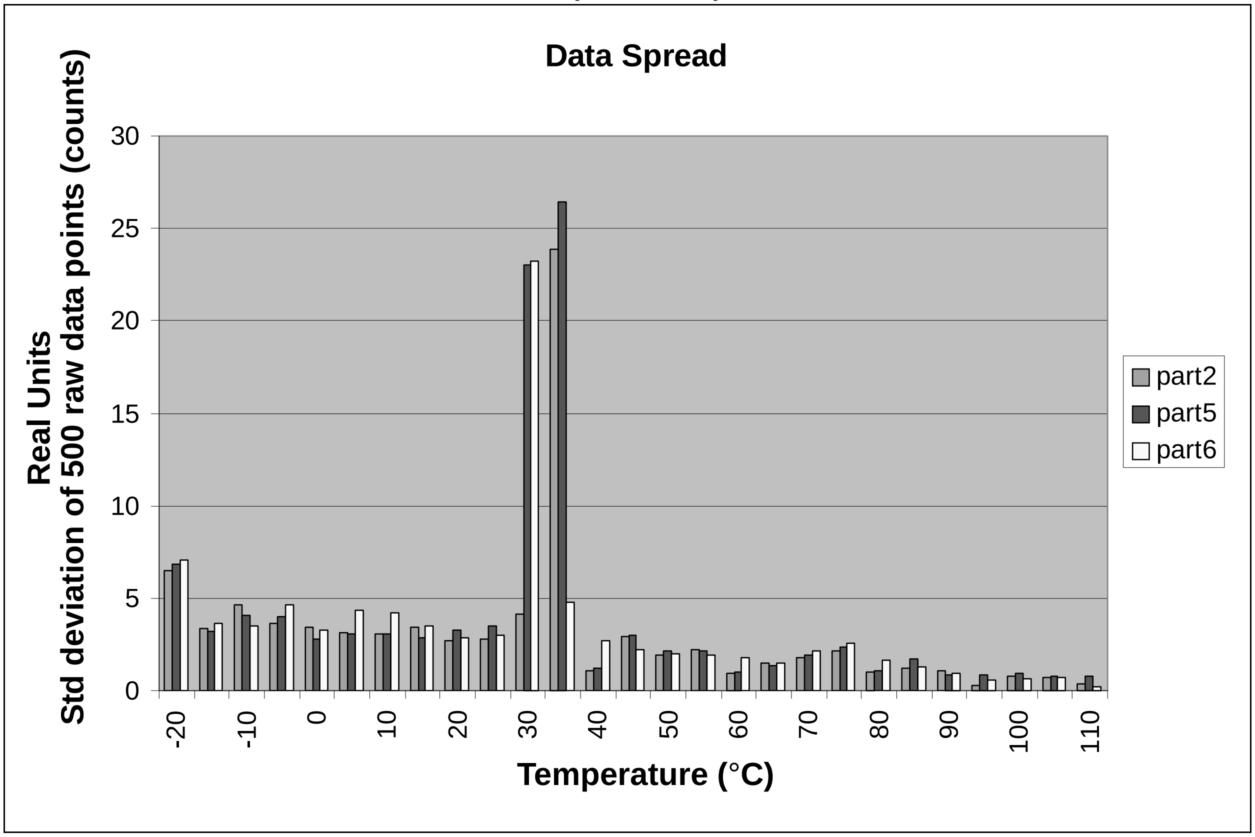


Figure 5A and Figure 5B illustrate the calculated uncalibrated "COUNTS per degree C" and "OFFSET" for each of the eight tested parts.

FIGURE 5A: COUNTS/°C

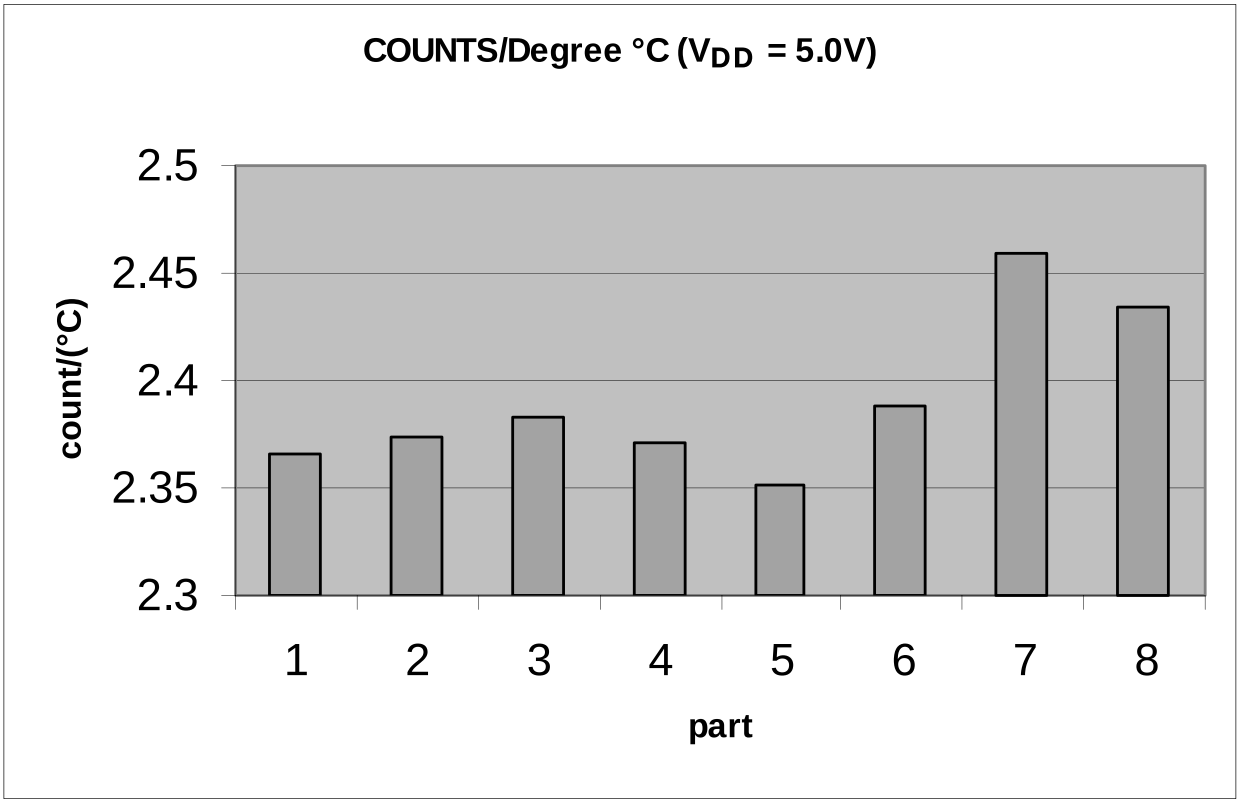
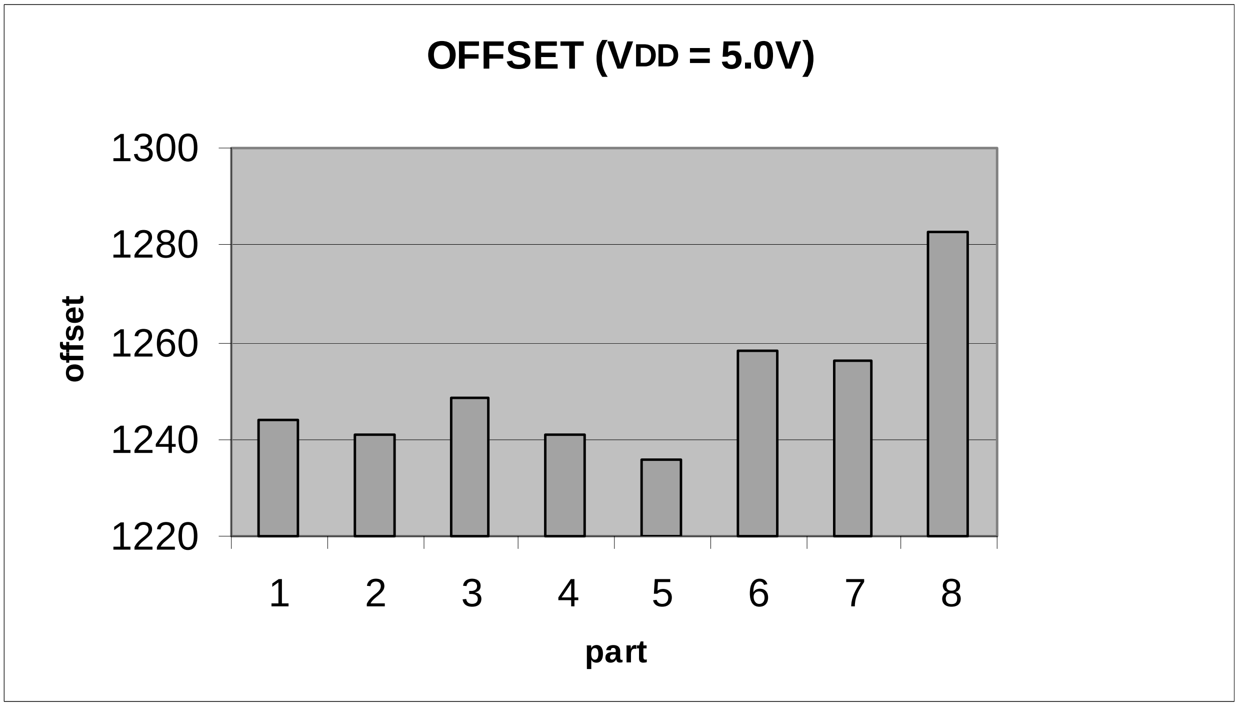


FIGURE 5B: OFFSET



CONCLUSION

The temperature dependence of the WDT timer oscillator is useful as a rough temperature measurement system, however, variations due to process differences and power supply will also have a significant effect on the WDT. Therefore, temperature calibration of each system for the slope and offset of the WDT/temperature function will be required to obtain reasonable accuracy.

MEMORY USAGE

101	words, program memory
11	bytes, data memory

APPENDIX A: SOURCE CODE

```
MPASM 02.30 Released         TSTAT2~1.ASM   9-15-1999  13:06:10         PAGE  1


LOC  OBJECT CODE     LINE SOURCE TEXT
  VALUE

         00001
;*************************************************************************************
         00002 ;This program demonstrates how the WDT and TMR0(reference timer) may be used for
         00003 ;rough temperature measurements. No filtering/debounce or algorithm is applied on
         00004 ;the raw data. The raw un-calibrated COUNTS are output to a PIC16C54C for transmittal
         00005 ;to a PC. GP<1:0> are used for data communication and GP3 is used as an output
               ;enable.
         00006 ;In typical applications, users will need to add code to cover WDT time out when not
         00007 ;taking rough temperature measurements. WDT tracking register WDTSTAT bit 0 used to
         00008 ;indicate if WDT timeouts are being used for rough temp measurements or in the normal
         00009 ;application.
         00010 ;
         00011 ;
         00012 ;       Program:        TSTAT2~1.ASM
         00013 ;       Revision Date:  9/7/99 Compatibility with MPlab 4.11
         00014 ;
         00015 ;
         00016 ;
         00017
;*************************************************************************************
         00018
         00019
         00020         LIST P=PIC12C509A;, F=INHX8M
         00021         #include "P12C509A.INC"
         00001         LIST
         00002 ; P12C509A.INC  Standard Header File, Version 1.00    Microchip Technology, Inc.
         00108         LIST
         00022
0FFF 0FFE 00023        __CONFIG _MCLRE_OFF & _CP_OFF & _WDT_ON & _IntRC_OSC
         00024
         00025 ;;
         00026 ;       declare registers
         00027
         00028 ;Note *
         00029 ;       All core program variables in page 0
         00030 ;
         00031
         00032         cblock          0x07    ;bank 0
```



```
0000007  T_COUNT:2                              ;counter for # of times tmr0 rolls (lo/hi byte)
00000009  SCREEN                                 ;screen register for tmr0 roll over
0000000A  DUMP                                   ;holding register
0000000B  BIT_COUNT                              ;# of bits to be sent
0000000C  WDTSTAT                                ;status register of wdt being used in
                                                 ;temperature or normal application mode

0000000D  TEMP6                                  ;temp register used by routines
0000000E  TEMP7                                  ;
0000000F  TEMP8                                  ;

                  endc
          ;
          ;
          ;;

0000              org      0x00
```

```
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LOC  OBJECT CODE     LINE SOURCE TEXT
  VALUE

0000 0025 00051          movwf   OSCCAL          ;load osc calibration for IntRC
0001 0C01 00052          movlw   b'00000001'     ;clear bus driver latch
0002 0026 00053          movwf   GPIO            ;
0003 0CFF 00054          movlw   b'11111111'     ;disable bus drivers
0004 0006 00055          tris    GPIO            ;
0005 04A3 00056          bcf     STATUS,PA0      ;set bank pointers to page 0
0006 04A4 00057          bcf     FSR,5           ;set address map to page 0
0007 04C4 00058          bcf     FSR,6
0008 0A09 00059          goto    Resetvector
          00060
          00061 ;;
          00062 ;       main memory
          00063
          00064
          00065          ;reset vector
0009      00066 Resetvector                      ;
          00067
0009 0C8B 00068          movlw   b'10001011'     ;load option register word
000A 0002 00069          option                  ;
          00070
          00071          ;check for power on reset
000B 0783 00072          btfss   STATUS,NOT_TO   ;must test condition of TO=1
000C 0A1B 00073          goto    Wdtest          ;to tell if power on reset.
          00074                                  ;there is no sleep mode support.
          00075                                  ;if not a POR, must be a WDT reset.
          00076                                  ;jump to the POR or WDT routines.
          00077
          00078 ;;
          00079          ;power on reset handler
000D      00080 P_reset                          ;initializtion routine
          00081
000D 0C00 00082          movlw   0x00            ;clear counters for measurement
000E 0027 00083          movwf   T_COUNT         ;
000F 0028 00084          movwf   T_COUNT+1       ;
0010 002C 00085          movwf   WDTSTAT         ;clear wdt tracking register
          00086
          00087
0011 050C 00088          bsf     WDTSTAT,0       ;set tracking register bit 0 to
          00089                                  ;indicate that wdt timeouts are being
          00090                                  ;used for rough temp measurements.
          00091                                  ;This register is typically set elsewhere
          00092                                  ;in a real application but for the
          00093                                  ;purposes of this example, is set here.
          00094
          00095
          00096                  ;init timers
0012 0004 00097          clrwdt                  ;initialize wdt
0013 0C00 00098          movlw   0x00            ;initialize timer0
0014 0021 00099          movwf   TMR0            ;and allow to free run
          00100
0015 0A16 00101          goto    $+1             ;delay to let tmr0 go past
0016 0A17 00102          goto    $+1             ;screen point
0017 0A18 00103          goto    $+1             ;
```

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LOC  OBJECT CODE     LINE SOURCE TEXT
  VALUE

0018 0A19 00104         goto    $+1               ;
0019 0A1A 00105         goto    $+1               ;
          00106
001A 0A57 00107         goto    Countimer         ;branch to counting routine
          00109 ;;
          00110         ;test what type of interupt
001B      00111 Wdtest
          00112                 ;test for wdt in temp measure or normal mode
001B 070C 00113         btfss   WDTSTAT,0         ;test wdt mode tracking bit.
          00114                                   ;if =1 then is in temperature mode.
          00115                                   ;if =0 then is in normal app mode.
001C 0A64 00116         goto    Nontempwdt        ;vector to normal app wdt handler here.
          00117                                   ;
          00118
          00119                 ;wdt temperature handler
001D      00120 Wdtvector
          00121                 ;print raw uncalibrated data
          00122
001D      00123 Raw
001D 0C00 00124         movlw   b'00000000'       ;zero communications bus and wait
001E 0026 00125         movwf   GPIO              ;to transfer data
001F 0CFF 00126         movlw   b'11111111'       ;while looking for output enables
0020 0006 00127         tris    GPIO              ;
          00128
          00129
0021      00130 OE                                ;test to see if output is enabled
          00131
0021 0004 00132         clrwdt
0022 0206 00133         movf    GPIO,W            ;sample portb
0023 0E08 00134         andlw   b'00001000'       ;mask unwanted bits
0024 002A 00135         movwf   DUMP              ;move to temporary register for test
0025 0C08 00136         movlw   b'00001000'       ;do test
0026 008A 00137         subwf   DUMP,W            ;
0027 0743 00138         btfss   STATUS,Z          ;test carry bit to see if OE.
0028 0A21 00139         goto    OE                ;cannot proceed to send data if no OE
          00140                 ;
          00141
0029      00142 Print                             ;setup for xfering data
          00143
0029 0C00 00144         movlw   b'00000000'       ;clear data latch
002A 0026 00145         movwf   GPIO              ;
002B 0CFD 00146         movlw   b'11111101'       ;set tris register
002C 0006 00147         tris    GPIO              ;
002D 0C11 00148         movlw   0x11              ;setup bit counter
002E 002B 00149         movwf   BIT_COUNT         ;to send 2 bytes of data
          00150                 ;
          00151
002F      00152 Clock_en                          ;once clock setup, check for
          00153                                   ;complete sending of all 2 bytes
          00154
002F 02EB 00155         decfsz  BIT_COUNT,F       ;test if 16 bits sent
0030 0A32 00156         goto    Senddata          ;
```

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LOC  OBJECT CODE     LINE SOURCE TEXT
  VALUE

0031 0A62 00157         goto    Softreset       ;reinit to take another measurement
          00158                 ;
          00159
          00160
0032      00161 Senddata                        ;must figure out whether sending upper or
          00162                                 ;lower byte
          00163
0032 0C09 00164         movlw   0x09            ;test if upper byte or lower byte
0033 008B 00165         subwf   BIT_COUNT,W     ;
0034 0603 00166         btfsc   STATUS,C        ;check to see iv value is zero
0035 0A37 00167         goto    Lower_8         ;jump to send lo byte
0036 0A47 00168         goto    Upper_8         ;jump to send hi byte
          00169                 ;
          00170
0037      00171 Lower_8
          00172
0037      00173 Test_lo                         ;check for clock strobe from receiving
          00174                                 ;unit. Clock must be lo. Then go hi.
          00175
0037 0004 00176         clrwdt
0038 0206 00177         movf    GPIO,W          ;test for clock lo to see if ready
0039 002A 00178         movwf   DUMP            ;put in temp register
003A 060A 00179         btfsc   DUMP,0          ;
003B 0A37 00180         goto    Test_lo         ;
          00181                 ;
          00182
003C      00183 Test_hi                         ;check for clock strobe. Send only on lo to
          00184                                 ;hi clock transition
          00185
003C 0004 00186         clrwdt
003D 0206 00187         movf    GPIO,W          ;test for clock hi to see if send
003E 002A 00188         movwf   DUMP            ;put in temp register
003F 070A 00189         btfss   DUMP,0          ;
0040 0A3C 00190         goto    Test_hi         ;
          00191                 ;
          00192
0041      00193 Lower_8_send                    ;xmit data 1 bit at a time by rotating thru
          00194                                 ;carry and checking it's value
          00195
0041 0426 00196         bcf     GPIO,1          ;reset data line
0042 0327 00197         rrf     T_COUNT,F       ;rotate into carry to test for 1 or 0
0043 0603 00198         btfsc   STATUS,C        ;test for 1 or 0
0044 0526 00199         bsf     GPIO,1          ;clear sending bit
0045 0000 00200         nop
          00201                 ;
          00202
          00203
0046 0A2F 00204         goto    Clock_en        ;return to send next data bit
          00205                 ;
          00206                 ;
          00207
          00208
0047      00209 Upper_8
```

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LOC  OBJECT CODE     LINE SOURCE TEXT
  VALUE

         00210
         00211
0047     00212 Test_lo_u                         ;check for clock strobe from receiving
         00213                                   ;unit. Clock must be lo. Then go hi.
         00214
0047 0004 00215         clrwdt
0048 0206 00216         movf    GPIO,W           ;test for clock lo to see if ready
0049 002A 00217         movwf   DUMP             ;put in temp register
004A 060A 00218         btfsc   DUMP,0           ;
004B 0A47 00219         goto    Test_lo_u        ;
         00220                  ;
         00221
004C     00222 Test_hi_u                         ;check for clock strobe. Send only on lo to
         00223                                   ;hi clock transition
         00224
004C 0004 00225         clrwdt
004D 0206 00226         movf    GPIO,W           ;test for clock hi to see if send
004E 002A 00227         movwf   DUMP             ;put in temp register
004F 070A 00228         btfss   DUMP,0           ;
0050 0A4C 00229         goto    Test_hi_u        ;
         00230                  ;
         00231
0051     00232 Upper_8_send                      ;xmit data 1 bit at a time by rotating thru
         00233                                   ;carry and checking it’s value
         00234
0051 0426 00235         bcf     GPIO,1           ;reset data line
0052 0328 00236         rrf     T_COUNT+1,F      ;rotate into carry to test for 1 or 0
0053 0603 00237         btfsc   STATUS,C         ;test for 1 or 0
0054 0526 00238         bsf     GPIO,1           ;clear sending bit
0055 0000 00239         nop
         00240                  ;
         00241
         00242
0056 0A2F 00243         goto    Clock_en         ;return to send next data
         00244                  ;
         00245                  ;
         00246
         00247
         00248
         00249 ;;
         00250         ;counting routine
0057     00251 Countimer
         00252
         00253         ;test to see if timer0 rolls over
0057     00254 Tmr0_byte                                 ;count the number of tmr0’s
         00255
0057 0201 00256         movf    TMR0,W                   ;copy tmr0 value to working register
0058 0029 00257         movwf   SCREEN                   ;
0059 0C0A 00258         movlw   0x0A                     ;load masking value
005A 0089 00259         subwf   SCREEN,W                 ;subtraction to screen for FF -> 0
         00260                                          ;transition in tmr0
005B 0603 00261         btfsc   STATUS,C                 ;test carry flag for
005C 0A57 00262         goto    Tmr0_byte                ;loop back and test for FF -> 0
```



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LOC  OBJECT CODE     LINE SOURCE TEXT
  VALUE

         00263
         00264          ;increment count lo byte
005D 02A7 00265         incf    T_COUNT,F               ;incr count (lo byte) once for every
         00266                                          ;tmr0 roll over
005E 0743 00267         btfss   STATUS,Z                ;test zero flag to see if need to
         00268                                         ;increment hi byte of count (16 bit counter)
005F 0A57 00269         goto    Tmr0_byte               ;loop back and test until wdt reset
         00270
         00271          ;increment count hi byte
0060 02A8 00272         incf    T_COUNT+1,F             ;incr count (hi byte) once for every
         00273                                          ;T_COUNT roll over
0061 0A57 00274         goto    Tmr0_byte               ;loop back and test until wdt reset
         00275
         00276
         00277 ;;
         00278          ;soft reset routine
0062     00279 Softreset                                ;clear conditions and reset for another
         00280                                          ;rough temperature measurement
         00281
0062 0004 00282         clrwdt                          ;clear the wdt
0063 0A0D 00283         goto    P_reset                 ;return to reset checks
         00284
         00285
         00286 ;;
         00287          ;non-temp measurement mode wdt handler
0064     00288 Nontempwdt
0064 0A64 00289         goto $                          ;normal mode wdt timeout handler.
         00290                                          ;since only running in rough temp measure
         00291                                          ;mode, routine is just a place holder.
         00292
         00293
         00294 ;;
         00295          end


MEMORY USAGE MAP ('X' = Used,  '-' = Unused)

0000 : XXXXXXXXXXXXXXXX XXXXXXXXXXXXXXXX XXXXXXXXXXXXXXXX XXXXXXXXXXXXXXXX
0040 : XXXXXXXXXXXXXXXX XXXXXXXXXXXXXXXX XXXXX----------- ----------------
0FC0 : ---------------- ---------------- ---------------- ---------------X

All other memory blocks unused.

Program Memory Words Used:   101
Program Memory Words Free:   923


Errors   :     0
Warnings :     0 reported,     0 suppressed
Messages :     0 reported,     0 suppressed
```


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Microchip received QS-9000 quality system certification for its worldwide headquarters, design and wafer fabrication facilities in Chandler and Tempe, Arizona in July 1999. The Company's quality system processes and procedures are QS-9000 compliant for its PICmicro® 8-bit MCUs, KEELOQ® code hopping devices, Serial EEPROMs and microperipheral products. In addition, Microchip's quality system for the design and manufacture of development systems is ISO 9001 certified.

WORLDWIDE SALES AND SERVICE

AMERICAS

Corporate Office
2355 West Chandler Blvd.
Chandler, AZ 85224-6199
Tel: 480-792-7200 Fax: 480-792-7277
Technical Support: 480-792-7627
Web Address: http://www.microchip.com

Rocky Mountain
2355 West Chandler Blvd.
Chandler, AZ 85224-6199
Tel: 480-792-7966 Fax: 480-792-7456

Atlanta
500 Sugar Mill Road, Suite 200B
Atlanta, GA 30350
Tel: 770-640-0034 Fax: 770-640-0307

Austin
Analog Product Sales
8303 MoPac Expressway North
Suite A-201
Austin, TX 78759
Tel: 512-345-2030 Fax: 512-345-6085

Boston
2 Lan Drive, Suite 120
Westford, MA 01886
Tel: 978-692-3848 Fax: 978-692-3821

Boston
Analog Product Sales
Unit A-8-1 Millbrook Tarry Condominium
97 Lowell Road
Concord, MA 01742
Tel: 978-371-6400 Fax: 978-371-0050

Chicago
333 Pierce Road, Suite 180
Itasca, IL 60143
Tel: 630-285-0071 Fax: 630-285-0075

Dallas
4570 Westgrove Drive, Suite 160
Addison, TX 75001
Tel: 972-818-7423 Fax: 972-818-2924

Dayton
Two Prestige Place, Suite 130
Miamisburg, OH 45342
Tel: 937-291-1654 Fax: 937-291-9175

Detroit
Tri-Atria Office Building
32255 Northwestern Highway, Suite 190
Farmington Hills, MI 48334
Tel: 248-538-2250 Fax: 248-538-2260

Los Angeles
18201 Von Karman, Suite 1090
Irvine, CA 92612
Tel: 949-263-1888 Fax: 949-263-1338

Mountain View
Analog Product Sales
1300 Terra Bella Avenue
Mountain View, CA 94043-1836
Tel: 650-968-9241 Fax: 650-967-1590

New York
150 Motor Parkway, Suite 202
Hauppauge, NY 11788
Tel: 631-273-5305 Fax: 631-273-5335

San Jose
Microchip Technology Inc.
2107 North First Street, Suite 590
San Jose, CA 95131
Tel: 408-436-7950 Fax: 408-436-7955

Toronto
6285 Northam Drive, Suite 108
Mississauga, Ontario L4V 1X5, Canada
Tel: 905-673-0699 Fax: 905-673-6509

ASIA/PACIFIC

Australia
Microchip Technology Australia Pty Ltd
Suite 22, 41 Rawson Street
Epping 2121, NSW
Australia
Tel: 61-2-9868-6733 Fax: 61-2-9868-6755

China - Beijing
Microchip Technology Beijing Office
Unit 915
New China Hong Kong Manhattan Bldg.
No. 6 Chaoyangmen Beidajie
Beijing, 100027, No. China
Tel: 86-10-85282100 Fax: 86-10-85282104

China - Shanghai
Microchip Technology Shanghai Office
Room 701, Bldg. B
Far East International Plaza
No. 317 Xian Xia Road
Shanghai, 200051
Tel: 86-21-6275-5700 Fax: 86-21-6275-5060

Hong Kong
Microchip Asia Pacific
RM 2101, Tower 2, Metroplaza
223 Hing Fong Road
Kwai Fong, N.T., Hong Kong
Tel: 852-2401-1200 Fax: 852-2401-3431

India
Microchip Technology Inc.
India Liaison Office
Divyasree Chambers
1 Floor, Wing A (A3/A4)
No. 11, O'Shaugnessey Road
Bangalore, 560 025, India
Tel: 91-80-2290061 Fax: 91-80-2290062

Japan
Microchip Technology Intl. Inc.
Benex S-1 6F
3-18-20, Shinyokohama
Kohoku-Ku, Yokohama-shi
Kanagawa, 222-0033, Japan
Tel: 81-45-471- 6166 Fax: 81-45-471-6122

ASIA/PACIFIC (continued)

Korea
Microchip Technology Korea
168-1, Youngbo Bldg. 3 Floor
Samsung-Dong, Kangnam-Ku
Seoul, Korea
Tel: 82-2-554-7200 Fax: 82-2-558-5934

Singapore
Microchip Technology Singapore Pte Ltd.
200 Middle Road
#07-02 Prime Centre
Singapore, 188980
Tel: 65-334-8870 Fax: 65-334-8850

Taiwan
Microchip Technology Taiwan
11F-3, No. 207
Tung Hua North Road
Taipei, 105, Taiwan
Tel: 886-2-2717-7175 Fax: 886-2-2545-0139

EUROPE

Denmark
Microchip Technology Denmark ApS
Regus Business Centre
Lautrup hoj 1-3
Ballerup DK-2750 Denmark
Tel: 45 4420 9895 Fax: 45 4420 9910

France
Arizona Microchip Technology SARL
Parc d'Activite du Moulin de Massy
43 Rue du Saule Trapu
Batiment A - ler Etage
91300 Massy, France
Tel: 33-1-69-53-63-20 Fax: 33-1-69-30-90-79

Germany
Arizona Microchip Technology GmbH
Gustav-Heinemann Ring 125
D-81739 Munich, Germany
Tel: 49-89-627-144 0 Fax: 49-89-627-144-44

Germany
Analog Product Sales
Lochhamer Strasse 13
D-82152 Martinsried, Germany
Tel: 49-89-895650-0 Fax: 49-89-895650-22

Italy
Arizona Microchip Technology SRL
Centro Direzionale Colleoni
Palazzo Taurus 1 V. Le Colleoni 1
20041 Agrate Brianza
Milan, Italy
Tel: 39-039-65791-1 Fax: 39-039-6899883

United Kingdom
Arizona Microchip Technology Ltd.
505 Eskdale Road
Winnersh Triangle
Wokingham
Berkshire, England RG41 5TU
Tel: 44 118 921 5869 Fax: 44-118 921-5820

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